AMENDMENTS TO THE SPECIFICATION

Please replace paragraph [0019] with the following replacement paragraph [0019]:

Segment "2", 20, includes test control function 28. The test control function 28 controls the vector pattern, and also allows the vector pattern to be overridden by a second vector pattern. The test control function 28 includes commands designed to exercise global control of a tester on an entire vector or command code. For example, the test control function 28 includes commands to inhibit a test signal and control fault data. The test control function 28 also includes commands to inhibit other commands such as interrupt commands. As such, the test control function 28 provides an additional level of functionality of the vector "1" ~~18~~ 12, over the command codes function 26. Segment "3", 22, includes a function control 30. Thus, the test control function 28 increases flexibility in vector creation.

Please replace paragraph [0021] with the following replacement paragraph [0021]:

Segment "4", 24, includes the vector pattern 32 which is the pattern output file for the vector "1", ~~18~~ 12. The vector pattern 32 includes commands calling actual industry standard vector patterns used by the particular system to control the drivers which are delivering the test signal to the device under test. The vector pattern 32 may include modified standard vector patterns, as well. For example, the vector patterns 32 may call a standard square wave vector which has its pulse width modified by a specified amount. Segment "4", 24' allows additional functionality control of vector "1", ~~18~~ 12. For example, segment "4", 24, allows additional information such as further control instructions to be associated with the vector "1", 12.

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